

<b>Notice of References Cited</b>	Application/Control No. 10/624,148		Applicant(s)/Patent Under Reexamination TAWA ET AL	
	Examiner MUHAMMAD N EDUN		Art Unit 2655	Page 1 of 1

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X	B	US-6,590,851	07-2003	Kim et al.	369/112.01
X	C	US-6,650,612	11-2003	Matsuzaki et al.	369/112.05
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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